

<b>Notice of References Cited</b>	Application/Control No. 10/501,180	Applicant(s)/Patent Under Reexamination LICK ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	L	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N	EP 0 857 647 A1	08-1998	EP	Ockelmann	
	O	WO 99/54863	10-1999	WO	Lee et al.	
	P					
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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